

<b>Notice of References Cited</b>	Application/Control No. 10/015,613	Applicant(s)/Patent Under Reexamination BAUDISCH, PATRICK	
	Examiner Aaron M. Richer	Art Unit 2676	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

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